

SDLS080

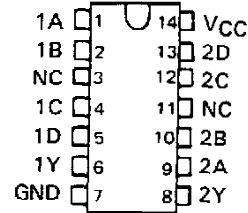
DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

SN5422, SN54LS22, SN54S22,
SN7422, SN74LS22, SN74S22

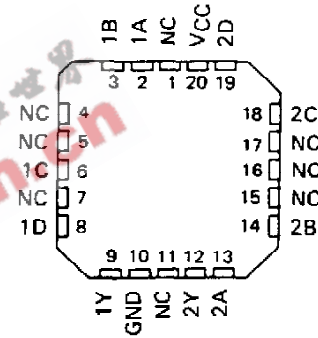
DECEMBER 1983 — REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

SN5422, SN54LS22, SN54S22 . . . J OR W PACKAGE
SN7422 . . . N PACKAGE
SN74LS22, SN74S22 . . . D OR N PACKAGE
(TOP VIEW)



SN54LS22, SN54S22 . . . FK PACKAGE
(TOP VIEW)



NC—No internal connection

description

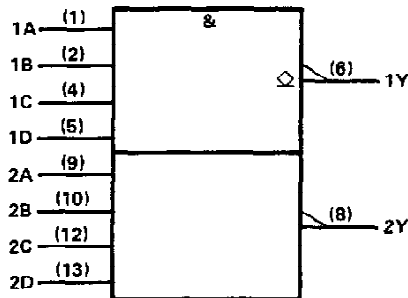
These devices contain two independent 4-input NAND gates. The open-collector outputs require pull-up resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher V_{OH} levels.

The SN5422, SN54LS22 and SN54S22 are characterized for operation over the full military temperature range of -55°C to 125°C . The SN7422, SN74LS22, and SN74S22 are characterized for operation from 0°C to 70°C .

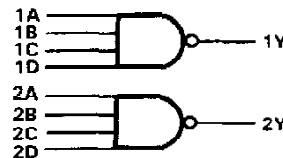
FUNCTION TABLE (each gate)

INPUTS				OUTPUT
A	B	C	D	Y
H	H	H	H	L
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H

logic symbol†



logic diagram



positive logic

$$Y = \overline{A \cdot B \cdot C \cdot D} \text{ or } Y = \overline{A} + \overline{B} + \overline{C} + \overline{D}$$

† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

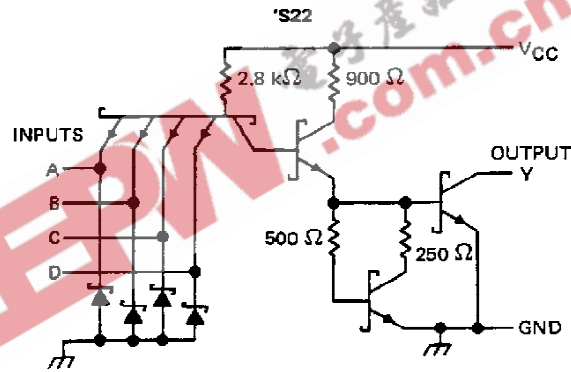
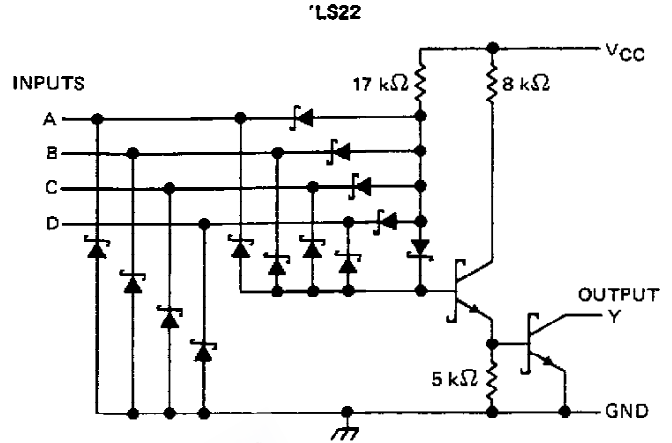
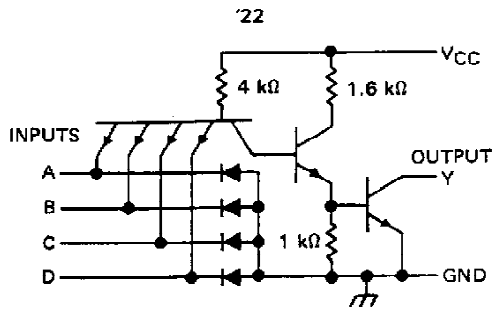
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TEXAS
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**SN5422, SN54LS22, SN54S22,
SN7422, SN74LS22, SN74S22**
DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (See Note 1)	7 V
Input voltage: '22, 'S22	5.5 V
'LS22	7 V
Operating free-air temperature range: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

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SN5422, SN7422
DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN5422			SN7422			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
V _{OH} High-level output voltage			5.5			5.5	V
I _{OL} Low-level output current			16			16	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN5422		SN7422		UNIT	
		MIN	TYP‡	MAX	MIN		TYP‡
V _{IK}	V _{CC} = MIN, I _I = -12 mA			-1.5		-1.5	V
I _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V					0.25	mA
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 5.5 V			0.25			
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4		0.2 0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1		1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V			40		40	μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-1.6		-1.6	mA
I _{CCH}	V _{CC} = MAX, V _I = 0		2	4		2 4	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V		6	11		6 11	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 4 k Ω, C _L = 15 pF		35	45	ns
t _{PHL}			R _L = 400 Ω, C _L = 15 pF		8	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



SN54LS22, SN74LS22 DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN54LS22			SN74LS22			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.7			0.8	V
V_{OH} High-level output voltage			5.5			5.5	V
I_{OL} Low-level output current			4			8	mA
T_A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54LS22			SN74LS22			UNIT
		MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}	$V_{CC} = \text{MIN.}$, $I_I = -18 \text{ mA}$			-1.5			-1.5	V
I_{OH}	$V_{CC} = \text{MIN.}$, $V_{IL} = \text{MAX.}$, $V_{OH} = 5.5 \text{ V}$			0.1			0.1	mA
V_{OL}	$V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V
	$V_{CC} = \text{MIN.}$, $V_{IH} = 2 \text{ V.}$, $I_{OL} = 8 \text{ mA}$					0.35	0.5	
I_I	$V_{CC} = \text{MAX.}$, $V_I = 7 \text{ V}$			0.1			0.1	mA
I_{IH}	$V_{CC} = \text{MAX.}$, $V_I = 2.7 \text{ V}$			20			20	μA
I_{IL}	$V_{CC} = \text{MAX.}$, $V_I = 0.4 \text{ V}$			-0.4			-0.4	mA
I_{CCH}	$V_{CC} = \text{MAX.}$, $V_I = 0$		0.4	0.8		0.4	0.8	mA
I_{CCL}	$V_{CC} = \text{MAX.}$, $V_I = 4.5 \text{ V}$		1.2	2.2		1.2	2.2	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$.

switching characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^\circ\text{C}$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{PLH}	Any	Y	$R_L = 2 \text{ k}\Omega$, $C_L = 15 \text{ pF}$		17	32	ns
t_{PHL}					15	28	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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SN54S22, SN74S22

DUAL 4-INPUT POSITIVE-NAND GATES WITH OPEN-COLLECTOR OUTPUTS

recommended operating conditions

	SN54S22			SN74S22			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage				0.8			V
V _{OH} High-level output voltage				5.5			V
I _{OL} Low-level output current				20			mA
T _A Operating free-air temperature	-55			125			°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†	SN54S22			SN74S22			UNIT	
		MIN	TYP‡	MAX	MIN	TYP‡	MAX		
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.2			-1.2	V	
I _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, V _{OH} = 5.5 V						0.25	mA	
	V _{CC} = MIN, V _{IL} = 0.7 V, V _{OH} = 5.5 V			0.25					
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 20 mA			0.5			0.5	V	
I _I	V _{CC} = MAX, V _I = 5.5 V			1			1	mA	
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			50			50	μA	
I _{IL}	V _{CC} = MAX, V _I = 0.5 V			-2			-2	mA	
I _{CCH}	V _{CC} = MAX, V _I = 0			3	6.6		3	6.6	mA
I _{CCL}	V _{CC} = MAX, V _I = 4.5 V			10	18		10	18	mA

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	Any	Y	R _L = 280 Ω, C _L = 15 pF	2	5	7.5	ns
t _{PHL}				2	4.5	7	ns
t _{PLH}			R _L = 280 Ω, C _L = 50 pF	7.5		ns	
t _{PHL}				7		ns	

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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